

Composing graph theory and deep neural networks to evaluate SEU type soft error effects

Balakrishnan, Aneesh; Lange, Thomas; Glorieux, Maximilien; Alexandrescu, Dan; **Jenihhin, Maksim** 9th Mediterranean Conference on Embedded Computing (MECO'2020), Budva, Montenegro, 8-11 June 2020 2020
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Enabling cross-layer reliability and functional safety assessment through ML-based compact models

Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

Gate-level graph representation learning : a step towards the improved stuck-at faults analysis

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Machine learning clustering techniques for selective mitigation of critical design features

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Machine learning to tackle the challenges of transient and soft errors in complex circuits

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On antagonism between side-channel security and soft-error reliability in BNN inference engines

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On the estimation of complex circuits functional failure rate by machine learning techniques

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Tau lepton identification and reconstruction : a new frontier for jet-tagging ML algorithms

Lange, Thomas; Nandan, Saswati; Pata, Joosep; **Tani, Laurits**; Veelken, Christian Computer physics communications 2024 / art. 109095 <https://doi.org/10.1016/j.cpc.2024.109095>

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The validation of graph model-based, gate level low-dimensional feature data for machine learning applications

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Understanding multidimensional verification : where functional meets non-functional

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